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APPLICATION NO.	F	ILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
10/723,701	11/26/2003		Michael J. Berman	03-1494	7831	
24319	7590	06/27/2005		EXAM	EXAMINER	
LSI LOGIC CORPORATION 1621 BARBER LANE				KOBERT, RUSSELL MARC		
MS: D-106				ART UNIT	PAPER NUMBER	
MILPITAS, CA 95035				2829		

DATE MAILED: 06/27/2005

Please find below and/or attached an Office communication concerning this application or proceeding.

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	Application No.	Applicant(s)					
Office Action Summany	10/723,701	BERMAN ET AL.					
Office Action Summary	Examiner	Art Unit					
7, 444,410,547,541	Russell M. Kobert	2829					
The MAILING DATE of this communication app Period for Reply	ears on the cover sheet with the c	orrespondence address					
A SHORTENED STATUTORY PERIOD FOR REPLY THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1.13 after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a reply - If NO period for reply is specified above, the maximum statutory period w - Failure to reply within the set or extended period for reply will, by statute, Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).	36(a). In no event, however, may a reply be time within the statutory minimum of thirty (30) days will apply and will expire SIX (6) MONTHS from cause the application to become ABANDONE	nely filed s will be considered timely. the mailing date of this communication. D (35 U.S.C. § 133).					
Status							
2a) ☐ This action is FINAL . 2b) ☑ This 3) ☐ Since this application is in condition for allowar							
Disposition of Claims							
4) ☐ Claim(s) 1-18 is/are pending in the application. 4a) Of the above claim(s) is/are withdrawn from consideration. 5) ☐ Claim(s) is/are allowed. 6) ☐ Claim(s) 1-18 is/are rejected. 7) ☐ Claim(s) is/are objected to. 8) ☐ Claim(s) are subject to restriction and/or election requirement.							
Application Papers							
9) ☐ The specification is objected to by the Examine 10) ☑ The drawing(s) filed on 26 November 2003 is/a Applicant may not request that any objection to the Replacement drawing sheet(s) including the correct 11) ☐ The oath or declaration is objected to by the Ex	re: a) \square accepted or b) \square object drawing(s) be held in abeyance. See ion is required if the drawing(s) is object.	e 37 CFR 1.85(a). jected to. See 37 CFR 1.121(d).					
Priority under 35 U.S.C. § 119							
 12) Acknowledgment is made of a claim for foreign a) All b) Some * c) None of: 1. Certified copies of the priority documents 2. Certified copies of the priority documents 3. Copies of the certified copies of the priority application from the International Bureau * See the attached detailed Office action for a list 	s have been received. s have been received in Applicati rity documents have been receive u (PCT Rule 17.2(a)).	on No ed in this National Stage					
Attachment(s)							
 Notice of References Cited (PTO-892) Notice of Draftsperson's Patent Drawing Review (PTO-948) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08) Paper No(s)/Mail Date 	4) Interview Summary Paper No(s)/Mail Di 5) Notice of Informal F 6) Other:						

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1. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that

form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

(e) the invention was described in (1) an application for patent, published under section 122(b), by another filed in the United States before the invention by the applicant for patent or (2) a patent granted on an application for patent by another filed in the United States before the invention by the applicant for patent, except that an international application filed under the treaty defined in section

351(a) shall have the effects for purposes of this subsection of an application filed in the United States only if the international application designated the United States and was published under Article 21(2)

of such treaty in the English language.

2. Claims 1-18 are rejected under 35 U.S.C. 102(e) as being anticipated by Hirao

(6788082).

Hirao anticipates (in each of the combined figures) a device and method for measuring

resistances associated with electrical contacts of a contact ring used in a semiconductor

wafer electroplating process, comprising:

a substrate (102);

a conductive pattern on said substrate (inherent to the Metal Plate 102 because there

would have to exist some form of conduction between the Probe Card Checker 101 and

each individual probe pin [P₁ - P_N] on the Metal Plate), said conductive pattern

electrically contactable with the electrical contacts of the contact ring (see circular ring

located at center of probe card 4); and

resistance measurement circuitry connected to said conductive pattern, said resistance

measurement circuitry configured to send test signals to said conductive pattern and

configured to receive signals from the conductive pattern and measure the resistances

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associated with the electrical contacts of the contact ring (col 5, In 36 - col 6, In 2); as

recited in claims 1 and 12.

As to claim 2, Hirao anticipates the substrate is at least one of a silicon substrate and a

metal substrate (Metal Plate 102).

As to claims 3 and 13, having the resistance measurement circuitry configured to

communicate signals to an external device, the signals relating to resistances to the

electrical contacts of the contact ring is considered inherent to the operation of the

Probe Card Checker 101.

As to claims 4-11 and 14-18 having a battery to power the resistance measurement

circuitry, having input/output circuitry connected to the conductive pattern, having

multiplexer circuitry connected to the conductive pattern, resistance determination

circuitry and the remaining claimed components and operational characteristics is

considered to be within the scope of Hirao.

A shortened statutory period for response to this action is set to expire three month(s) from the date of this letter. Failure to respond within the period for response will cause the application to become abandoned. 35 U.S.C. 133

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Russell Kobert whose telephone number is (571) 272-1963. The Examiner's Supervisor, Nestor R. Ramirez, can be reached at (571) 272-

2034. For an automated menu of Tech Center 2800 phone numbers call (571) 272-

2800.

Russell M. Kobert Patent Examiner Group Art Unit 2829

June 20, 2005

VINH NGUYEN
PRIMARY EXAMINER

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